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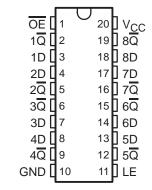
- State-of-the-Art EPIC-IIB™ BiCMOS Design Significantly Reduces Power Dissipation
- Latch-Up Performance Exceeds 500 mA Per JEDEC Standard JESD-17
- Typical V<sub>OLP</sub> (Output Ground Bounce)
   1 V at V<sub>CC</sub> = 5 V, T<sub>A</sub> = 25°C
- High-Drive Outputs (-32-mA I<sub>OH</sub>, 64-mA I<sub>OL</sub>)
- Package Options Include Plastic Small-Outline (DW) and Shrink Small-Outline (DB) Packages, Ceramic Chip Carriers (FK), and Plastic (N) and Ceramic (J) DIPs

#### description

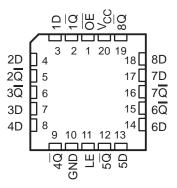
The 'ABT533 are 8-bit transparent D-type latches with 3-state outputs designed specifically for driving highly capacitive or relatively low-impedance loads. They are particularly suitable for implementing buffer registers, I/O ports, bidirectional bus drivers, and working registers.

When the latch-enable (LE) input is high, the  $\overline{Q}$  outputs follow the complements of the data (D) inputs. When LE is taken low, the  $\overline{Q}$  outputs are latched at the inverse of the levels set up at the D inputs. The 'ABT533 provides inverted data at its outputs.

SN54ABT533 . . . J PACKAGE SN74ABT533 . . . DB, DW, OR N PACKAGE (TOP VIEW)



SN54ABT533 . . . FK PACKAGE (TOP VIEW)



A buffered output-enable  $(\overline{OE})$  input can be used to place the eight outputs in either a normal logic state (high or low logic levels) or a high-impedance state. In the high-impedance state, the outputs neither load nor drive the bus lines significantly. The high-impedance state and the increased drive provide the capability to drive bus lines without need for interface or pullup components.

OE does not affect the internal operations of the latches. Previously stored data can be retained or new data can be entered while the outputs are in the high-impedance state.

To ensure the high-impedance state during power up or power down,  $\overline{OE}$  should be tied to  $V_{CC}$  through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

The SN74ABT533 is available in TI's shrink small-outline package (DB), which provides the same I/O pin count and functionality of standard small-outline packages in less than half the printed-circuit-board area.

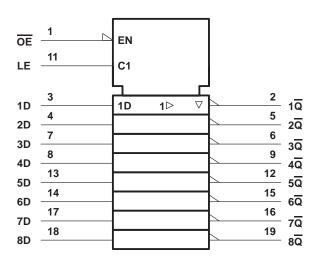
The SN54ABT533 is characterized for operation over the full military temperature range of  $-55^{\circ}$ C to  $125^{\circ}$ C. The SN74ABT533 is characterized for operation from  $-40^{\circ}$ C to  $85^{\circ}$ C.

EPIC-IIB is a trademark of Texas Instruments Incorporated

## FUNCTION TABLE (each latch)

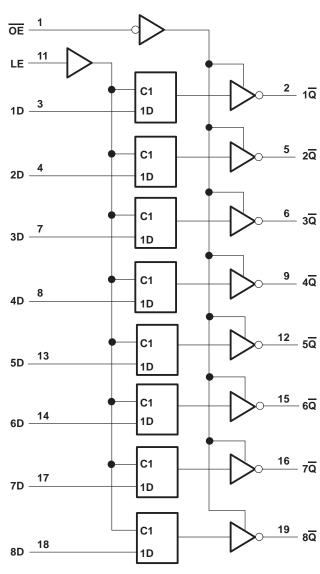
	INPUTS		OUTPUT
OE	LE	D	Q
L	Н	Н	L
L	Н	L	н
L	L	Χ	$\overline{Q}_0$
Н	Х	Χ	Z

### logic symbol†



<sup>&</sup>lt;sup>†</sup>This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

### logic diagram (positive logic)



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### absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage range, V <sub>CC</sub>	0.5 V to 7 V
Input voltage range, V <sub>I</sub> (see Note 1)	
Voltage range applied to any output in the high state or power-off state,	, V <sub>O</sub> – 0.5 V to 5.5 V
Current into any output in the low state, IO: SN54ABT533	96 mA
SN74ABT533	128 mA
Input clamp current, I <sub>IK</sub> (V <sub>I</sub> < 0)	
Output clamp current, I <sub>OK</sub> (V <sub>O</sub> < 0)	
Maximum power dissipation at $T_A = 55^{\circ}C$ (in still air) (see Note 2): DB p	package 0.6 W
DW	package 1.6 W
	ackage 1.3 W
Storage temperature range	•

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.

2. The maximum package power dissipation is calculated using a junction temperature of 150°C and a board trace length of 750 mils, except for the N package, which has a trace length of zero. For more information, refer to the *Package Thermal Considerations* application note in the 1994 *ABT Advanced BiCMOS Technology Data Book*, literature number SCBD002B.

### recommended operating conditions (see Note 3)

		SN54ABT533		SN74ABT533		UNIT
		MIN	MAX	MIN	MAX	UNII
Vcc	Supply voltage	4.5	5.5	4.5	5.5	V
VIH	High-level input voltage	2	EN	2		V
$V_{IL}$	Low-level input voltage		0.8		0.8	V
٧ <sub>I</sub>	Input voltage	0 <	Vcc	0	Vcc	V
I <sub>OH</sub>	High-level output current	ζ)	-24		-32	mA
loL	Low-level output current	700	48		64	mA
Δt /Δν	Input transition rise or fall rate	A)	10		10	ns/V
TA	Operating free-air temperature	-55	125	-40	85	°C

NOTE 3: Unused or floating inputs must be held high or low.

## SN54ABT533, SN74ABT533 OCTAL TRANSPARENT D-TYPE LATCHES WITH 3-STATE OUTPUTS

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## electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS		Т	A = 25°C	;	SN54ABT533		SN74ABT533		UNIT	
PARAMETER	TEST CONDITIONS			MIN	TYP†	MAX	MIN	MAX	MIN	MAX	UNIT
VIK	$V_{CC} = 4.5 \text{ V},$	I <sub>I</sub> = -18 mA				-1.2		-1.2		-1.2	V
	$V_{CC} = 4.5 \text{ V},$	$I_{OH} = -3 \text{ mA}$		2.5			2.5		2.5		
\/a	$V_{CC} = 5 \text{ V}, \qquad I_{OH} = -3 \text{ mA}$			3			3		3		v
VOH	V <sub>CC</sub> = 4.5 V	$I_{OH} = -24 \text{ mA}$		2			2				V
	VCC = 4.5 V	$I_{OH} = -32 \text{ mA}$		2*					2		
Voi	V <sub>CC</sub> = 4.5 V	I <sub>OL</sub> = 48 mA				0.55		0.55			V
VOL	VCC = 4.5 V	I <sub>OL</sub> = 64 mA				0.55*				0.55	V
lį	$V_{CC} = 5.5 \text{ V},$	V <sub>I</sub> = V <sub>CC</sub> or GNE	)			±1		±1		±1	μΑ
lozh	$V_{CC} = 5.5 \text{ V},$	V <sub>O</sub> = 2.7 V				10‡		10‡		10‡	μΑ
lozL	$V_{CC} = 5.5 \text{ V},$	V <sub>O</sub> = 0.5 V				-10‡		-10‡		-10‡	μΑ
l <sub>off</sub>	$V_{CC} = 0$ ,	$V_I$ or $V_O \le 4.5 \text{ V}$				±150	5			±150	μΑ
ICEX	$V_{CC} = 5.5 \text{ V},$	V <sub>O</sub> = 5.5 V	Outputs high			50	90	50		50	μΑ
ΙΟ <sup>§</sup>	$V_{CC} = 5.5 \text{ V},$	V <sub>O</sub> = 2.5 V		-50	-140	-180	-50	-180	-50	-180	mA
	V <sub>CC</sub> = 5.5 V, I <sub>O</sub> = 0, V <sub>I</sub> = V <sub>CC</sub> or GND		Outputs high		1	250		250		250	μΑ
Icc		Outputs low		24	30		30		30	mA	
	1 1 - 100 01 01	ND	Outputs disabled		0.5	250		250		250	μΑ
	V <sub>CC</sub> = 5.5 V,		Outputs enabled			1.5		1.5		1.5	
$\Delta I_{CC}$	One input at 3.4 V, Other inputs at V <sub>CC</sub> or GND	Outputs disabled			1.5		1.5		1.5	mA	
		Control inputs			1.5		1.5		1.5		
C <sub>i</sub>	V <sub>I</sub> = 2.5 V or 0.	5 V			3						pF
Co	$V_0 = 2.5 \text{ V or } 0$	0.5 V			9						pF

<sup>\*</sup> On products compliant to MIL-STD-883, Class B, this parameter does not apply.

## timing requirements over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (see Figure 1)

			V <sub>CC</sub> =	= 5 V, 25°C	SN54AI	ВТ533	SN74ABT533		UNIT
			MIN	MAX	MIN	MAX	MIN	MAX	
t <sub>W</sub>	t <sub>W</sub> Pulse duration, LE high		3.3		3.3	10,71	3.3		ns
t <sub>su</sub>	Setup time, data before LE↓	High or low	2.1		2.1	110	2.1		ns
t <sub>h</sub>	Hold time, data after LE $\downarrow$	High or low	1.5§		1.5§		1.5§		ns

<sup>†</sup> All typical values are at  $V_{CC} = 5 \text{ V}$ .

<sup>&</sup>lt;sup>‡</sup>This data sheet limit may vary among suppliers.

<sup>§</sup> Not more than one output should be tested at a time, and the duration of the test should not exceed one second.

 $<sup>\</sup>P$  This is the increase in supply current for each input that is at the specified TTL voltage level rather than V<sub>CC</sub> or GND.

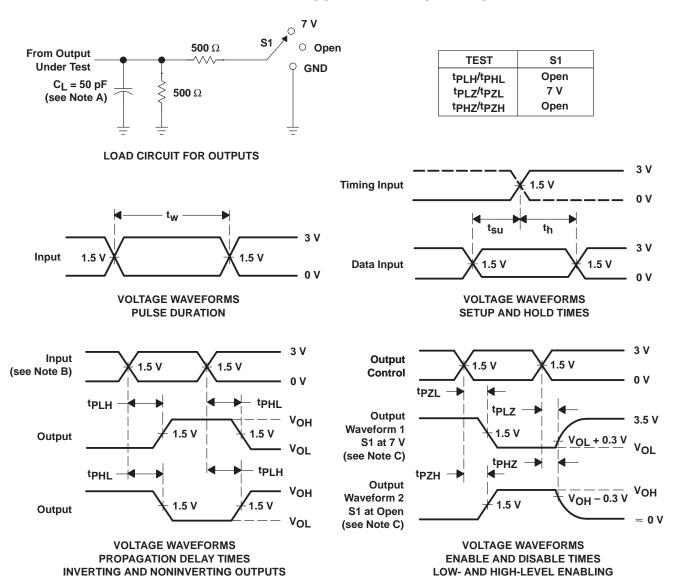
### SN54ABT533, SN74ABT533 OCTAL TRANSPARENT D-TYPE LATCHES WITH 3-STATE OUTPUTS

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# switching characteristics over recommended ranges of supply voltage and operating free-air temperature, $C_L$ = 50 pF (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	FROM TO (INPUT) (OUTPUT)		V <sub>CC</sub> = 5 V, T <sub>A</sub> = 25°C		SN54ABT533		SN74ABT533		UNIT
	(INPOT)	(001701)	MIN	TYP	MAX	MIN	MAX	MIN	MAX	
t <sub>PLH</sub>	D	Q	1.9	4.2	5.4	1.9	6.7	1.9	6.4	ns
<sup>t</sup> PHL		σ	3.1	4.9	6.3	3.1	6.9	3.1	6.6	115
t <sub>PLH</sub>	LE	Q	2.7	4.9	6.2	2.7	7.6	2.7	7.3	ns
t <sub>PHL</sub>		LE	g	3.5	5.4	6.8	3.5 <	7.5	3.5	7.3
<sup>t</sup> PZH	ŌĒ	Q	1.6	3.7	4.8	1.6	5.8	1.6	5.7	ns
tPZL	OE	g	2.4	4.2	6.2	2.4	6.9	2.4	6.7	115
t <sub>PHZ</sub>	ŌĒ	Q	2.8	5.1	6.2	2.8	7.2	2.8	6.9	no
tPLZ		γ	2	4.1	6	2	6.9	2	6.5	ns

#### PARAMETER MEASUREMENT INFORMATION



NOTES: A. C<sub>L</sub> includes probe and jig capacitance.

- B. All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  10 MHz,  $Z_O = 50 \Omega$ ,  $t_f \leq 2.5$  ns.  $t_f \leq 2.5$  ns.
- C. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- D. The outputs are measured one at a time with one transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms



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